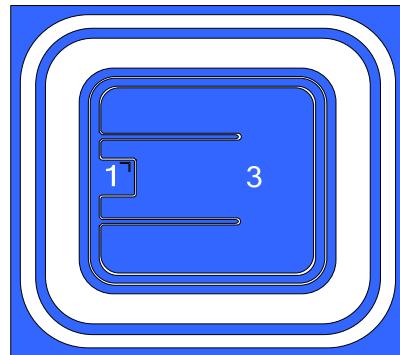


## 3VD396500YL HIGH VOLTAGE MOSFET CHIPS

### DESCRIPTION

- 3VD396500YL is a High voltage N-Channel enhancement mode power MOS-FET chip fabricated in advanced silicon epitaxial planar technology;
- Advanced termination scheme to provide enhanced voltage-blocking capability;
- Avalanche Energy Specified;
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode;
- The chips may packaged in TO-220 type and the typical equivalent product is 840;
- The packaged product is widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers;
- Die size: 4.13mm\*3.98mm;
- Chip Thickness:  $300\pm20\mu\text{m}$ ;
- Top metal: Al, Backside Metal: Ag.



PAD1-Gate    PAD3-Source

CHIP TOPOGRAPHY

### ABSOLUTE MAXIMUM RATINGS ( $T_{\text{amb}}=25^\circ\text{C}$ )

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	500	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current	$I_D$	8.0	A
Power Dissipation (TO-220 Package)	$P_D$	74	W
Operation Junction Temperature	$T_J$	-55~+150	$^\circ\text{C}$
Storage Temperature	$T_{STG}$	-55~+150	$^\circ\text{C}$

### ELECTRICAL CHARACTERISTICS ( $T_{\text{amb}}=25^\circ\text{C}$ )

Parameter	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	500	-	-	V
Gate Threshold Voltage	$V_{TH}$	$V_{GS}= V_{DS}, I_D=250\mu\text{A}$	2.0	-	4.0	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=500\text{V}, V_{GS}=0\text{V}$	-	-	1.0	$\mu\text{A}$
Static Drain- Source On State Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=4.0\text{A}$	-	0.76	0.9	$\Omega$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 30\text{V}, V_{DS}=0\text{V}$	-	-	$\pm 100$	nA
Source-Drain Diode Forward on Voltage	$V_{FSD}$	$I_S=8.0\text{A}, V_{GS}=0\text{V}$	-	-	1.4	V